

## Sample Results Summary Sheet

Please return this form to the Curator for each allocated Sample

**Sample ID:** RA-QD02-0063

**PI:** Tomoki Nakamura

**Type and date of analysis performed:**

XRD Jan/28/2011~ Feb/3/2011

FE-SEM Feb/19/2011~ Feb/28/2011

**Elements or phases identified:** (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)

XRD : OI, LPx, PI

FE-SEM : OI

**Contaminant phases identified:** (Al, SUS, carbon particles, etc.)

N/A

**Sample handling:**

XRD

Attached to carbon fiber with resin.

FE-SEM

Exposed in atmosphere.

Polished by M cross

C-coated (20 nm)

**State of sample pre-analysis:**

Attached to carbon fiber with resin. (XRD)

Polished section with resin embedded (FE-SEM)

**State of sample post-analysis:**

Attached to carbon fiber with resin. (XRD)

Polished section with resin embedded, C-coated (FE-SEM)

N<sub>2</sub> hold in sample holder.

**Analysis data Notes:** (summary of the attached analysis data and/or images)

See attached sheets.

